

FACULTY OF ELECTRICAL
ENGINEERING**SUBJECT CARD**

Name in Polish: **Techniki mikroprocesorowe w systemach pomiarowych**
 Name in English: **Microprocessor techniques in measuring systems**
 Main field of study (if applicable): **Electrical Engineering**
 Specialization (if applicable): **Industrial Electrical Engineering**
 Level and form of studies: **2nd level, part-time**
 Kind of subject: **optional**
 Subject code: **ELR043369**
 Group of courses: **NO**

	Lecture	Classes	Laboratory	Project	Seminar
Number of hours of organized classes in University (ZZU):	22		11		
Number of hours of total student workload (CNPS):	54		27		
Form of crediting:	examination		crediting with grade		
For group of courses mark (X) final course:					
Number of ECTS points:	2		1		
including number of ECTS points for practical (P) classes :			1		
including number of ECTS points for direct teacher-student contact (BK) classes:	1.40		0.70		

PREREQUISITES RELATING TO KNOWLEDGE, SKILLS AND OTHER COMPETENCES

1. Has a basic knowledge of the industrial measurement. Knows the principles of operation of sensors in the measurement of non-electrical quantities.
2. Has organized knowledge in the scope of microprocessor system architectures.

SUBJECT OBJECTIVES

- C1. To broaden and organize knowledge in the scope of microprocessor transducers and devices for measuring the electrical and non-electrical quantities used in standard and special measuring systems.
 C2. To acquire the ability to formulate and solve problems related to modelling virtual measuring systems
 C3. To acquire the ability to integrate knowledge in the fields of metrology, control engineering, electronics and data transmission.

SUBJECT EDUCATIONAL EFFECTS*relating to knowledge:*

- PEK_W01 Has broadened and organized knowledge in the scope of structure and architecture of microprocessor transducers of electrical and non-electrical quantities.
 PEK_W02 Has deepened knowledge in the scope of transmission and acquisition of data in the devices and systems for measuring the electrical and non-electrical quantities.
 PEK_W03 Has organized knowledge in the scope of smart measuring transducer usage

relating to skills:

- PEK_U01 Has the ability to formulate and solve problems related to modelling measuring systems.
 PEK_U02 Has the ability to integrate knowledge in the fields of metrology, control engineering, electronics and measurement data transmission.

relating to social competences:

- PEK_K01 Has the ability to think and act in a creative and entrepreneurial manner. Has the ability to adequately assign priorities related to implementation of a given task.

PROGRAMME CONTENT

Form of classes - lecture		Number of hours:
Lec 1	Smart Transducer - definitions, structure, standardization, applications	2
Lec 2	Static and dynamic characters	2
Lec 3	Signal conditioning, processing of A/D and D/A	2
Lec 4	Model ISO/OSI, wireless transmission, microcontrollers in smart transducer	2
Lec 5	Microprocessors in industrial measuring systems - standard CAN	2
Lec 6	Microprocessors in industrial measuring systems - standard HART, MODBUS	2
Lec 7	Microprocessors in industrial measuring systems - standard PROFIBUS, physical layer	2
Lec 8	Environmental graphic design of instruments and measurement systems, DAQ	2
Lec 9	Standard LonWorks, PLC	2
Lec 10	Smart Transducer - examples of applications of systems measuring. Part I.	2
Lec 11	Smart Transducer - examples of applications of systems measuring. Part II.	2
Total hours:		22

Form of classes - laboratory		Number of hours:
Lab 1	Health and Safety Regulations, laboratory of assessment rules. Introduction to Programming in LabVIEW	1
Lab 2	Get DAC	2
Lab 3	Virtual measuring of temperature part I - creating SubVI	2
Lab 4	Virtual measuring of temperature part II - graphics	2
Lab 5	Plotting waveform functions, modify charts, acquisition and analysis of measurement data	2
Lab 6	Smart transducer - communication, summary of activities	2
Total hours:		11

TEACHING TOOLS USED

- N1. Traditional lectures using audiovisual techniques
 N2. Laboratory test conducted exercises in student groups
 N3. Consultation

EVALUATION OF SUBJECT EDUCATIONAL EFFECTS ACHIEVEMENT

Evaluation <i>F - forming (during semester) P - concluding (at semester end)</i>	Educational effect number	Way of evaluating educational effect achievement
F1(W)	PEK_W01 PEK_W02 PEK_W03	Examination
P(W)	P=F1	
F1(L)	PEK_U01 PEK_U02 PEK_K01	Rating tasks performed during laboratory classes P = F
P(L)	P=F1	

PRIMARY AND SECONDARY LITERATURE

PRIMARY LITERATURE:

- [1] Lysik P.T., Inteligentna technika pomiarowa. Politechnika Radomska, Wydawnictwo Radom 2001
 [2] Nawrocki W., Rozproszone systemy pomiarowe. WKiŁ sp. z oo., Warszawa 2006
 [3] Tłaczała W., Środowisko LabVIEW w eksperymencie wspomaganym komputerowo, WN-T, Warszawa

SECONDARY LITERATURE:

- [1] Nawrocki W., Komputerowe systemy pomiarowe. WKiŁ sp. z oo., Warszawa 2002, 2006
 [2] Świsulski D., Komputerowa technika pomiarowa. Oprogramowanie wirtualnych przyrządów pomiarowych w LabVIEW. Agenda Wydawnicza PAK-u, Warszawa, 2005
 [3] Chruściel M., LabVIEW w praktyce, Wydawnictwo BTC, Legionowo 2008
 [4] <http://www.LabVIEW.pl>
 [5] <http://www.modbus.pl>
 [6] <http://www.ni.com>
 [7] <http://www.profibus.org.pl>

SUBJECT SUPERVISOR

Krzysztof Podlejski, krzysztof.podlejski@pwr.edu.pl

MATRIX OF CORRELATION BETWEEN EDUCATIONAL EFFECTS FOR SUBJECT
ELR043369 - Microprocessor techniques in measuring systems
 AND EDUCATIONAL EFFECTS FOR MAIN FIELD OF STUDY **Electrical Engineering**
 AND SPECIALIZATION **Industrial Electrical Engineering**

Subject educational effect	Correlation between subject educational effect and educational effects defined for main field of study and specialization (if applicable)	Subject objectives	Programme content	Teaching tool number
PEK_W01	S2ETP_W11	C.1	Lec1 Lec2 Lec3 Lec4 Lec5 Lec6 Lec7 Lec8 Lec9 Lec10 Lec11	N.1 N.3
PEK_W02	S2ETP_W11	C.1	Lec1 Lec4 Lec5 Lec6 Lec7 Lec9	N.1 N.3
PEK_W03	S2ETP_W11	C.1	Lec1 Lec5 Lec6 Lec7 Lec9 Lec10 Lec11	N.1 N.3
PEK_U01	S2ETP_U09	C.2 C.3	Lab1 Lab2 Lab3 Lab4 Lab5 Lab6	N.2 N.3
PEK_U02	S2ETP_U09	C.2 C.3	Lab3 Lab4 Lab5 Lab6	N.2 N.3
PEK_K01	K2ETK_K06	C.1 C.2 C.3	Lec1 Lec4 Lec5 Lec6 Lec7 Lec8 Lec9 Lec10 Lec11 Lab2 Lab3 Lab4 Lab5 Lab6	N.1 N.2 N.3